

Search Notes

Application/Control No.

10/822,725

Examiner

Pierre-Michel Bataille

Applicant(s)/Patent under
Reexamination

HOSHINO ET AL.

Art Unit

2186

SEARCHED

Class	Subclass	Date	Examiner
711	114 ; 112 113 ; 118 170		
707	102		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR